

<b>Notice of References Cited</b>	Application/Control No. 10/580,401		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner MEWALE AMBAYE		Art Unit 2472	Page 1 of 1

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*	B	US-2003/0084089	05-2003	Kurose et al.	709/200
*	C	US-7,215,640	05-2007	Matsubara, Daisuke	370/235
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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